# APPROVAL SHEET

Customer Name	:		
Customer P/N	:		
Frequency	:	32.768000	KHz
Aker Approved P/N	:	SMA-000032-2XL2T0	
Aker MPN	:	SMA-000032-2XL2T0	
Rev.	:	1	
ISSUE DATE	:	Jan.25.2019	

APPROVED	CHECKED	PREPARED
Leal		Kiku
APPROVED BY CUST	OMER	

# AKER TECHNOLOGY CO., LTD.

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Web: www.aker.com.tw

**RoHS** compliant



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APPROVED	:	Xtal	SHEET: 1 of 10

Kiku

REV . : 1

Rev.	Date	Reviser	Revise contents
1	2019/1/25	Kiku	Initial Released

PREPARED



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#### SMD CRYSTAL OSCILLATOR

#### 1. ELECTRICAL CHARACTERISTICS

■ Standard atmospheric conditions

Unless otherwise specified, the standard range of atmospheric conditions for making measurement and tests are as follow:

Ambient temperature: 25±5°C

Relative humidity : 40%~70%

If there is any doubt about the results, measurement shall be made within the following limits:

Ambient temperature: 25±3°C

Relative humidity : 40%~70%

AKER Model: SMA-221Cutting Model: AT CUT

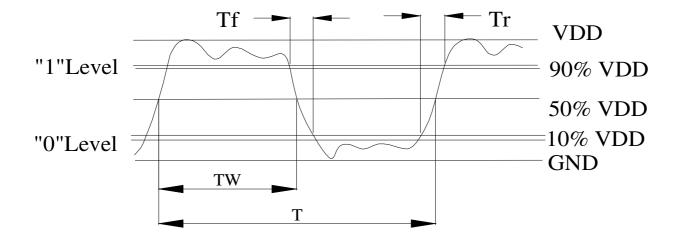
		Electrical Spec				
Parameters	Symbol	Min.	Typ.	Max.	Units.	Notes
Nominal Frequency		3	2.76800	0	KHz	
Frequency Stability			±30		ppm	
Supply Voltage	$V_{\mathrm{DD}}$		3.3±10%	)	V	
Output Load CMOS	CL		15		pF	
Aging			±3		ppm	First Year
Enable Control			Yes			Pad 1
Operating Temperature		-20	25	70	$^{\circ}\mathbb{C}$	
Storage Temperature Range		-55	?	125	$^{\circ}$	
Output Voltage High	VoH	2.97			V	
Output Voltage Low	VoL			0.33	V	
Input Current	Icc			5	mA	
Standby Current	Ist			10	μA	
Rise Time	Tr			100	ns	10%~90%V <sub>DD</sub> Level
Fall Time	Tf			100	ns	10%~90%V <sub>DD</sub> Level
Symmetry (Duty ratio)	TH/T	45	~	55	%	
Start-up Time	Tosc			35	ms	
Enable Voltage High	Vhi	70%V <sub>DD</sub>			V	
Disable Voltage Low	Vlo			30%VDD	V	
Output Enable Delay Time	T on			35	ms	
Output Disable Delay Time	T off			200	ns	

\*Please kindly be noted that AKER DO NOT guarantee parts quality which involves human security application.\*

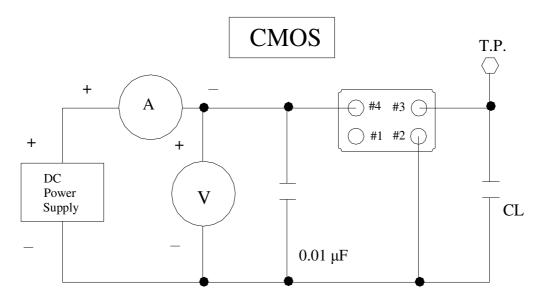


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# 2.C-MOS LOAD OUTPUT WAVEFORM



# 3. C-MOS LOAD TEST CIRCUIT



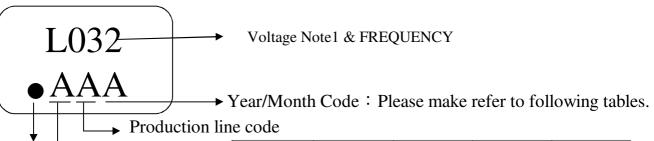
\*\*\*Because SMA series has no by pass capacitor. So,we recommend our customer to use capacitor  $0.01~\mu F$  in join Vcc and GND.



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#### 4. MARKING:

Pin1



AKER LOGO.

#### NOTE1:

NOIDI.	
T	5.0V TTL
С	4.5~5.0V CMOS
L	2.97~3.63V TTL&CMOS
R	2.8~3.0V CMOS
S	2.25~2.75V CMOS
Y	1.5~2.0V CMOS
Z	0.8~1.4V CMOS
W	Voltage Range CMOS

2007	2008	2009	2010
2011	2012	2013	2014
2015	2016	2017	2018
2019	2020	2021	2022
2023	2024	2025	2026
Α	N	a	n
В	P	b	р
С	Q	С	q
D	R	d	r
E	S	е	s
F	Т	f	t
G	U	g	u
Н	V	h	ν
J	W	j	w
K	X	k	х
L	Y	1	у
M	Z	m	Z
	2011 2015 2019 2023 A B C D E F G H J K	2011 2012 2015 2016 2019 2020 2023 2024  A N B P C Q D R E S F T G U H V J W K X L Y	2011         2012         2013           2015         2016         2017           2019         2020         2021           2023         2024         2025           A         N         a           B         P         b           C         Q         c           D         R         d           E         S         e           F         T         f           G         U         g           H         V         h           J         W         j           K         X         k           L         Y         l

#### 5. DIMENSION:

#### Enable / Disable Function

E/D (#1)	OUTPUT (#3)
HIGH (Open)	Operating
LOW	High impedance

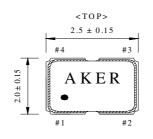
#### PIN FUNCTION

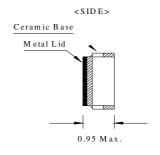
#1: Enable / Disable Control

#2: GND

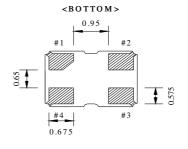
#3: OUTPUT

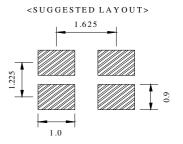
#4: VDD





(UNIT:mm)

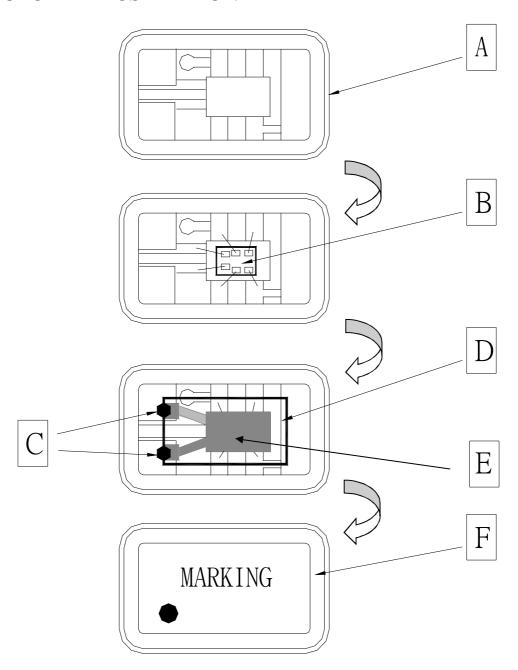






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# **6. STRUCTURE ILLUSTRATION**



	COMPONENTS	ONENTS MATERIALS		MPONENTS	MATERIALS
A	Base (Package)	Ceramic (Al2O3)+Kovar (Fe/Co/Ni)	D	Crystal blank	SiO <sub>2</sub>
В	IC chip		Е	Electrode	Cr / Ag
С	Conductive adhesive	Ag / Silicon resin	F	Lid	Fe/Co/Ni

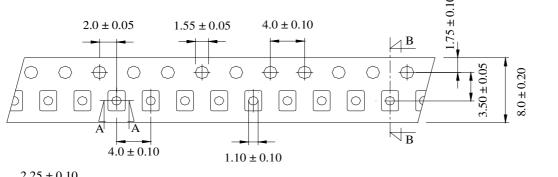


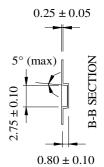
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#### 7. PACKING:

TAPE SPECIFICATION

(Unit:mm)

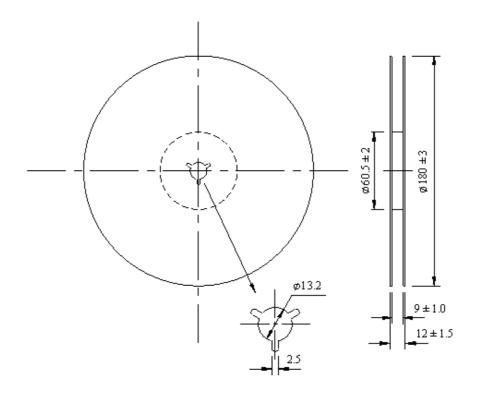






#### **OUTLINE DIMENSION**

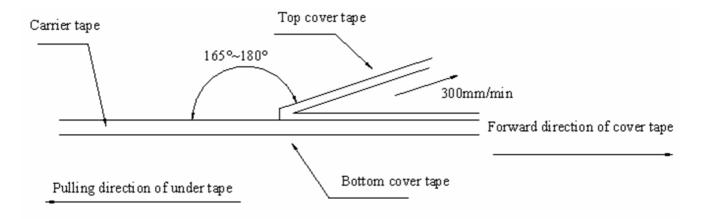
(Unit:mm)





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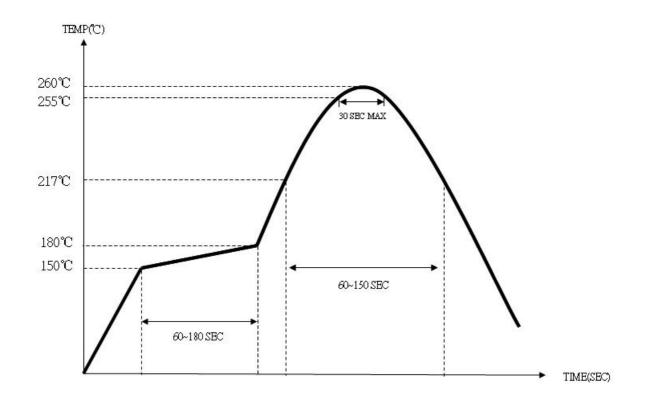
#### 8. COVER TAPE ADHESION STRENGTH:



\*\*\* In the case, the cover tape is pulled off under the above conditions, the cover tape adhesion strength should be 10.2g~71.4g Plastic tape: 10.2g~71.4g

(Cover tape adhesion strength)

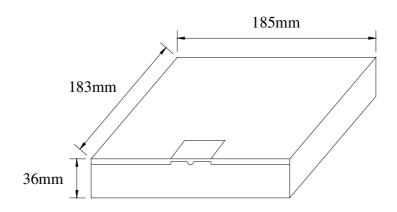
#### 9. SOLDERING REFLOW PROFILE





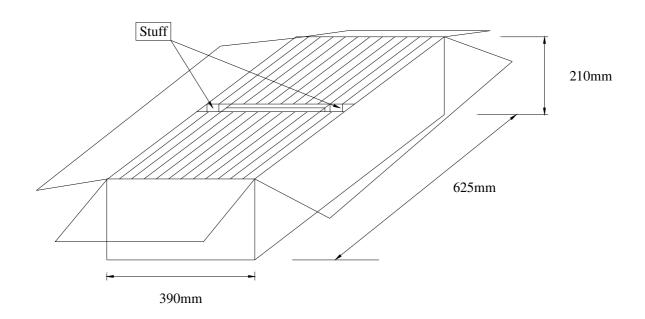
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# 10. PACKING:



BOX = 3000 PCS / REEL(MAX)





SMD product packs 32 BOX=The outside box packs (3000 PCS \* 32 BOX = 96000 PCS)(MAX)



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#### 11. MECHANICAL PERFORMANCE

TEST ITEMS	TEST METHODS AND TEST CONDITION	PERFORMANCE
11.1 Drop Test	The specimen is measured for its frequency before the test. It is then dropped from a hight of 100 cm or more as a free fall object onto a hard wooden plate of 30mm or more in thickness.  ( in accordance with JIS-C0044 )	
11.2 Vibration Test	The specimen is measured for its frequency before the test. Most them into X,Y and Z axes, respectively, for the vibration test. Vibration condition: Frequency range; 20 ~ 2000HZ Peak to peak amplitude: 1.52 mm Peak acceleration: 20G Sweep time: 20 minute / axis Pendicular total test time: 4 hours	To satisfy the electrical performance.
11.3 Resistance to Soldering Test	(in accordance with MIL-STD-883F: 2007.3)  The specimen is measured for its frequency before the test. Place the specimen on the belt of the converynace and let it pass through the reflow with the presetted temperature condition.  After passing twice the reflow place, the specimen under the referee condition for -~2 hours and then measure its electrical performance.  Temperature Condition of IR Simulation:  The temperature range of the preheated section is setted at 150 ~ 180°C for 60~120 sec. For the next section the temperature range is setted at 217~260°C for 45~90 sec. and within this time range the specimen should be able to sustain at the peak temperature,	
11.4 Fine Leak Test	260+/-3°C , for 10 sec long.  ( in accordance with JESD22-B106-B )  Place the specimen in a pressurized container and pressurize it with the detection gas ( mixed gas consisting of 95% or more helium ) for at least 2 hours. Complete the measurement of the concentration of helium within 30 min after taking it out from the pressurized container.	Less than $1.0*10^{-8} \text{ atm .c.c. / sec,}$ Helium
	( in accordance with MIL-STD-883F:1014.11 )  The referee condition.  Temperature 25 ± 2 °C  Humidity 44 ~ 55 %  Pressure 86 ~ 106 kPa  ( in accordance with MIL-STD-883E:1014.9 )	



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# 12. CLIMATIC RESISTANCE

TEST METHODS AND TEST CONDITION	PERFORMANCE
The specimen is measured for its frequency	
•	
-	
•	
_	
( in accordance with JIS-C0020 )	
The specimen is measured for its frequency	
	To satisfy the electrical
<u>*</u>	
	performance.
( in accordance with JIS-C0021 )	
The specimen is measured for its frequency	
before the test.	
Place the specimen in the testing chamber and	
kept it at the temperature of $+85 \pm 5$ °C and	
humidity of $85 \pm 5$ % for $168 \pm 6$ hours.and	
then take the specimen out and measure its	
electrical performance after leaving for 1 ~ 2	
hours under the referee condition.	
( in accordance with MIL-STD-883F:1004.7)	
The specimen is measured for its frequency	
before the test.	
Subject the specimen to the 100 cycles of	
temperature ranges stated below.	
	•
High temp . + $125 \pm 3$ °C ( $15\pm 3$ min).	
High temp . + $125 \pm 3$ °C ( $15\pm 3$ min).	
High temp . + $125 \pm 3$ °C ( $15\pm 3$ min). $2\sim 3$ min $2\sim 3$ min.	
$2\sim3$ min. Low temp55 ±3 °C (15± 3 min).	
$2 \sim 3 \text{ min.}$ $2 \sim 3 \text{ min.}$	
	before the test . Place the specimen in the chamber and kept it at the temperature of - $40 \pm 3^{\circ}\mathbb{C}$ for $168 \pm 6$ hours . Take the specimen out of the chamber and measure itselectrical performance after leaving $1^{\circ}$ 2 hours under the referee condition. ( in accordance with JIS-C0020 )  The specimen is measured for its frequency before the test . Place the specimen in the testing chamber and keep it at the temperature of $+125 \pm 3^{\circ}\mathbb{C}$ for $720 \pm 48$ hours. And then take the specimen out of the chamber and measure its electrical performance after leaving for $1^{\circ}$ 2 hours under the referee condition . ( in accordance with JIS-C0021 )  The specimen is measured for its frequency before the test . Place the specimen in the testing chamber and kept it at the temperature of $+85 \pm 5^{\circ}\mathbb{C}$ and humidity of $85 \pm 5^{\circ}\mathbb{C}$ for $168 \pm 6$ hours.and then take the specimen out and measure its electrical performance after leaving for $1^{\circ}$ 2 hours under the referee condition. ( in accordance with MIL-STD-883F: $1004.7$ )  The specimen is measured for its frequency before the test . Subject the specimen to the $100$ cycles of